

Technical Seminar on Atom Probe Tomography for 3D Atomic-Scale Characterization and Biomaterials Analysis

Robert M. Ulfing: CAMECA Instruments

September 11, 2019 | 12pm - 1pm

Pettit Microelectronics Building 102A

Lunch Provided with Registration

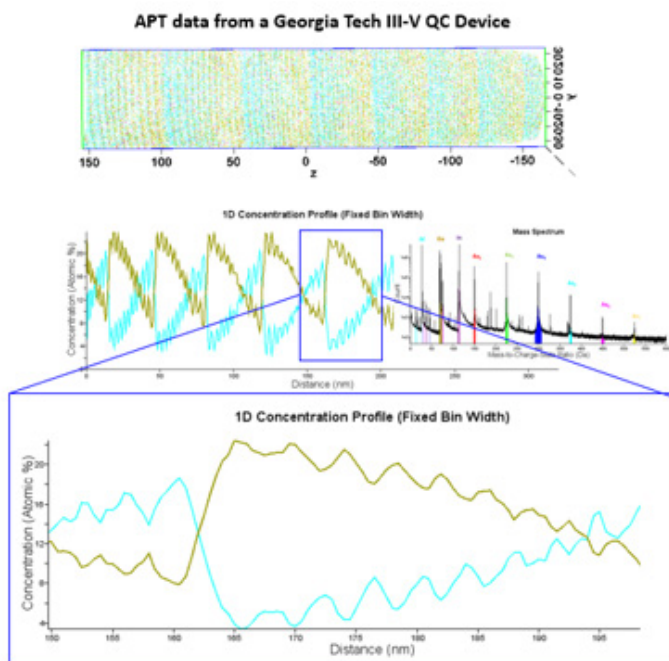
Atom Probe Tomography (APT) is the highest special resolution analytical characterization technique with high efficiency single atom detection for quantitative atom scale 3D compositional analysis and elemental mapping of chemical heterogeneities. This talk will cover APT operational theory, an introduction to sample prep and data reconstruction, and an overview of various applications. A commercial cryo-UHV solution for FIB-APT specimen transfer will also be presented which expands the application space for APT to biological materials, hydrogen containing materials, and surfaces prone to rapid oxidation.



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<https://tinyurl.com/CamekaAPT>

Robert M. Ulfing has played many roles at CAMECA (Imago) since 2001 and now works as a Product Manager for the atom probe products. Robert previously worked as a Sr. Process Engineer at Advanced Micro Devices sub-micron development center in Sunnyvale CA, and graduated from The University of Wisconsin-Madison with a BS in Nuclear Engineering (Reactor Operator at the department's 1MWt nuclear reactor) and a Masters in Materials Science and Engineering.

